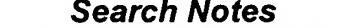


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/840,110	WEEL, MARTIN
	<b>Examiner</b> Oanh Duong	<b>Art Unit</b> 2155

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner